

Quantitative Modeling of Racetrack Memory

A Tradeoff among Area, Performance, and Power

Chao Zhang, ¹Guangyu Sun, ¹Weiqi Zhang,
Fan Mi, ²Hai Li, ³Weisheng Zhao

¹ Peking University, China

² University of Pittsburgh, U.S.A.

³ Beihang University, China



Outline

- **◆Background**
- Layout Modeling
- Case Study
- Conclusions



Non-Volatile Memory is Attractive

- High storage density
- Low standby power
- Good scalability
- Immunity to soft error

• • •

Universal Memory for all these layers?



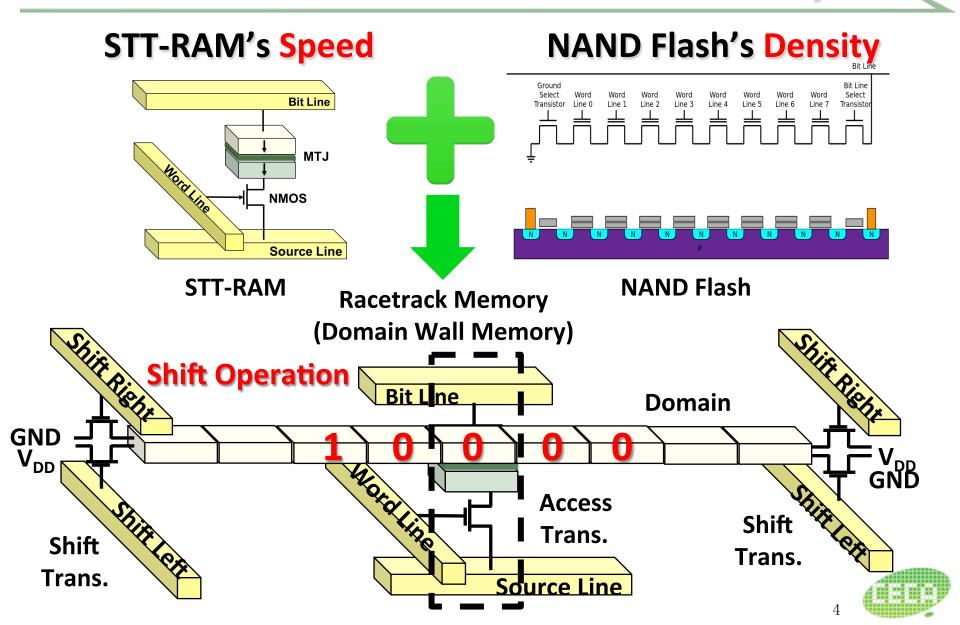
STT-RAM

PCM

Caches



Racetrack is a Potential Universal Memory



Related Work on RM

Physical level

- [Science'08], introduction of racetrack memory.
- [IEDM'11], a 256 cells demo die.
- [VLSI'09], [JAP'11], [JAP'12], Physical modeling.

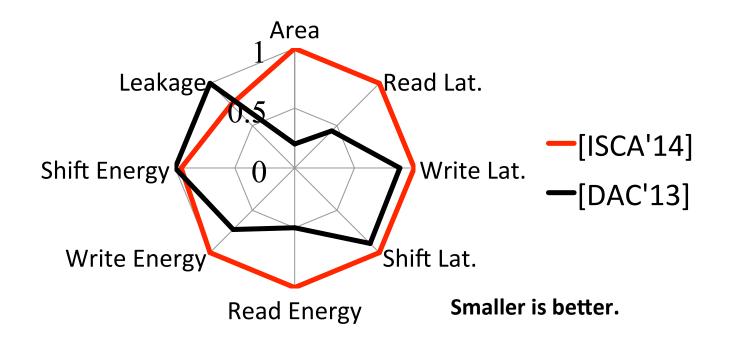
RM design is not fully exploited due to lack of circuit-level modeling

Architecture level

- ◆ Density: 2X~6X, Speed up: 60%~140% (over STT-RAM cache)
- [ISLPED'12, ISCA'14], large GPGPU caches
- [DAC'13, TC'14], cross-layer exploration and optimization.

RM Design Space is Huge!

Metrics used to describe a design



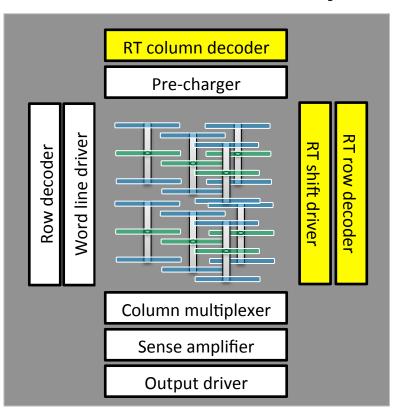
Modeling of RM is challenging



Challenges of Modeling RM Array

- Decoding is more complicated
 - Access port , domain
- Support for shift operation
 - Extra peripheral circuitry
 - Position registers
- Layout modeling is complicated
 - Cell has many parameters
 - Cells can be overlapped
 - Cell-Circuit co-optimization

Racetrack Memory





Outline

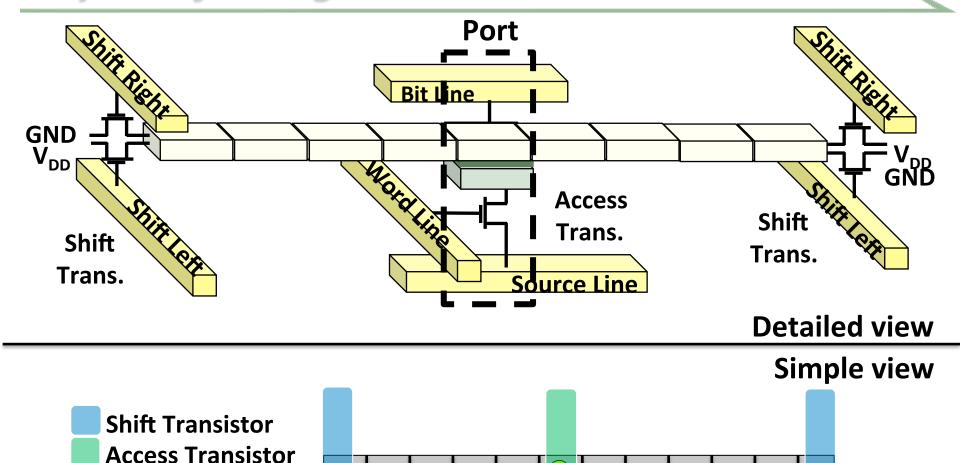
- **◆Background**
- **◆Layout Modeling**
- Case Study
- Conclusions



Layout of a Single Cell

Port

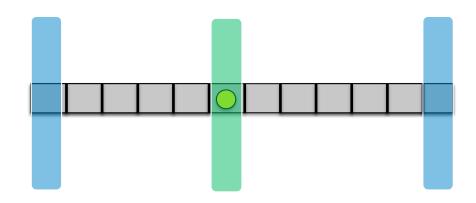
Racetrack





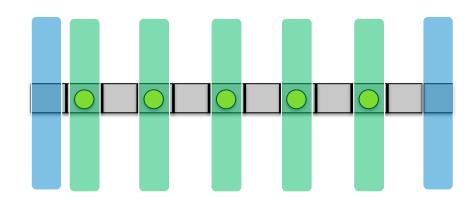
- Cell parameters
 - Racetrack length
 - Number of ports
 - Width of transistor
 - Domain size
 - Overhead domains
- Cell overlapping





- Cell parameters
 - Racetrack length
 - Number of ports
 - Width of transistor
 - Domain size
 - Overhead domains
- Cell overlapping

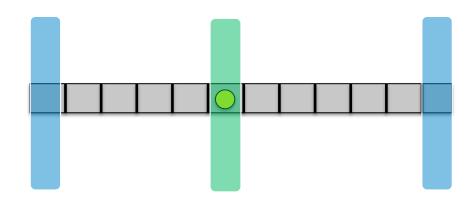






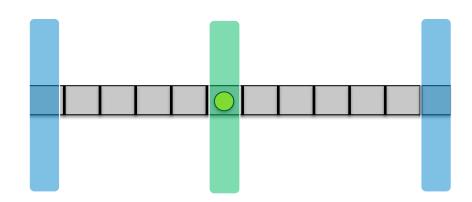
- Cell parameters
 - Racetrack length
 - Number of ports
 - Width of transistor
 - Domain size
 - Overhead domains
- Cell overlapping





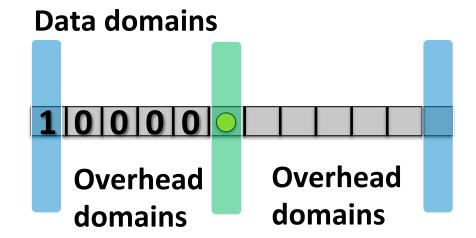
- Cell parameters
 - Racetrack length
 - Number of ports
 - Width of transistor
 - Domain size
 - Overhead domains
- Cell overlapping





- Cell parameters
 - Racetrack length
 - Number of ports
 - Width of transistor
 - Domain size
 - Overhead domains
- Cell overlapping

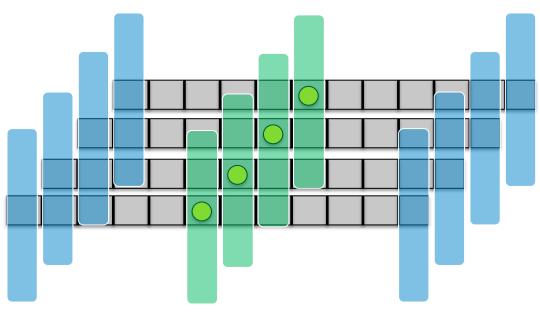






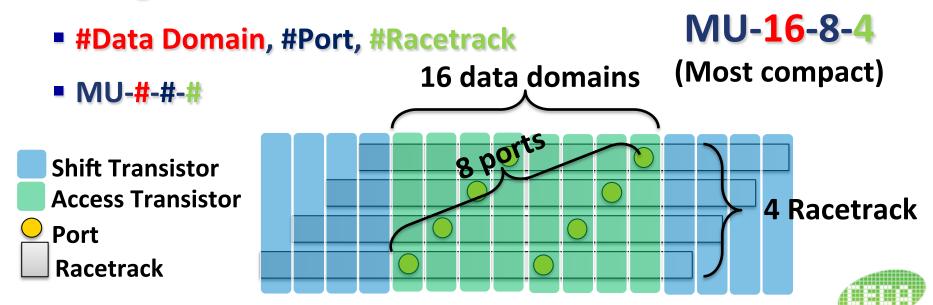
- Cell parameters
 - Racetrack length
 - Number of ports
 - Width of transistor
 - Domain size
 - Overhead domains
- ◆ Cell overlapping





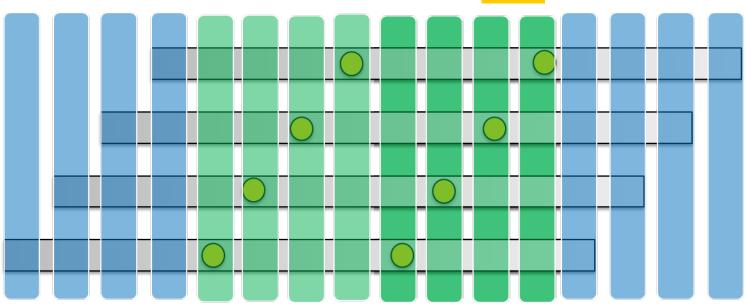
Macro Unit

- Use macro unit to build an array.
- Definition
 - Several cells that are overlapped with each other
- Configuration



Interaction: #Port vs. Racetrack Length



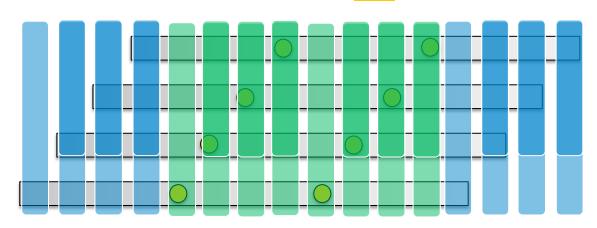


$$N_P \le N_{Pmax} = \frac{L_{RT} - N_D L_D 2^{1 - N_{PPR}}}{L_{NMOS} + G_{MOS}}$$



Interaction: #RT vs. Transistor Width

Max. RT: 3



$$N_{RT} \le N_{RTmax} = \lfloor \frac{W_{MOS} - W_{via}}{W_{RT} + G_{RT}} \rfloor$$

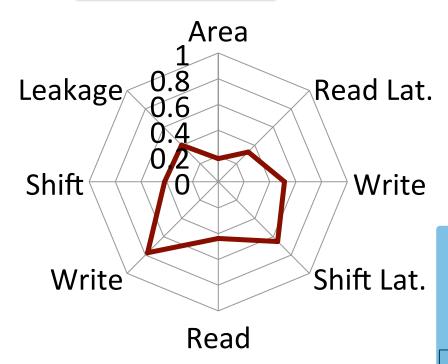
Cell (MU)-Circuit co-optimization is also important

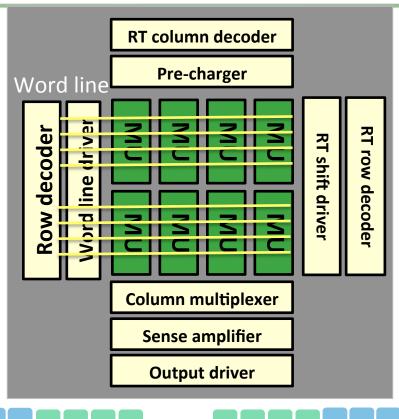


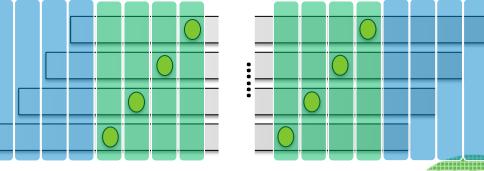
Cell-Circuit Co-optimization

- Optimization for Area
 - More cells and ports

in a macro unit

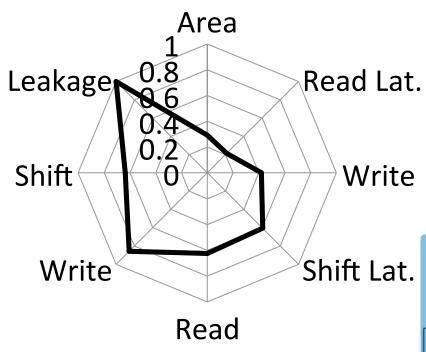


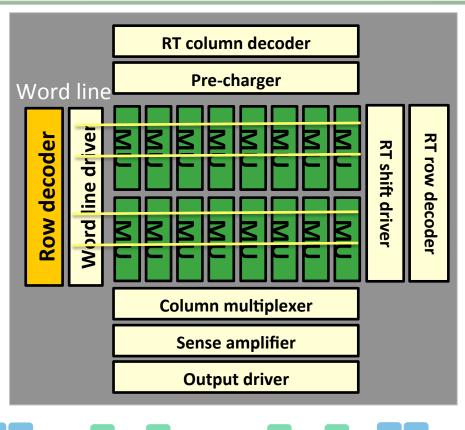


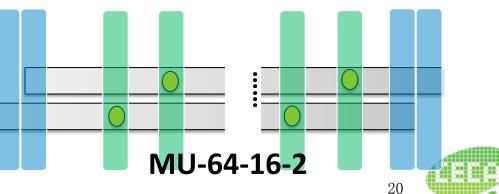


Cell-Circuit Co-optimization

- Read Latency
 - Trade density for speed

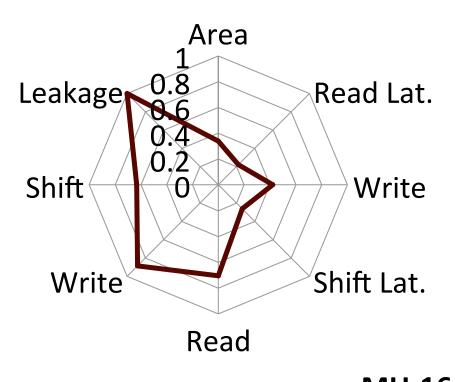


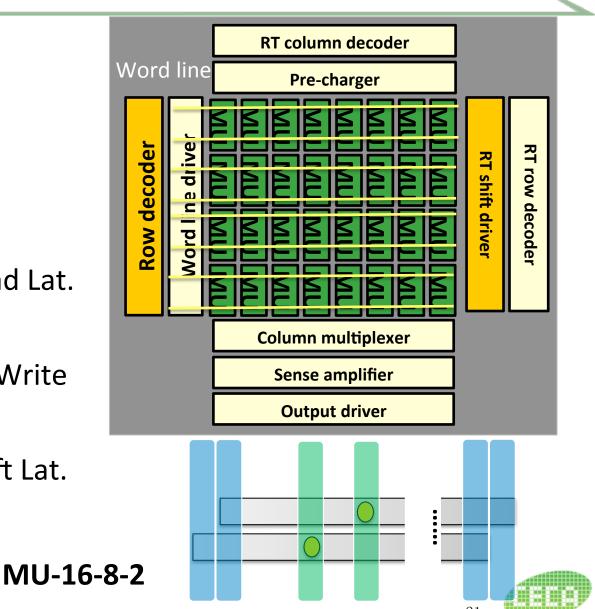




Cell-Circuit Co-optimization

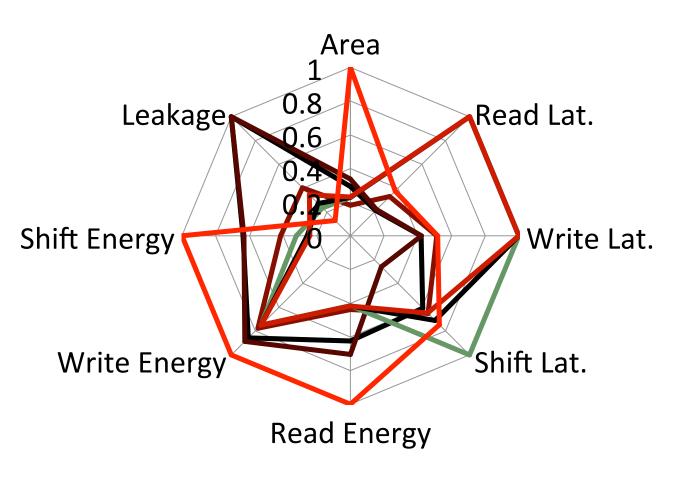
- Shift Latency
 - Short racetrack





Optimization Targets

Different target focuses on different metric.



- **—**Area
- —Read Latency
- —Write Latency
- Shift Latency
- —Read Energy
- —Write Energy
- —Shift Energy
- Leakage Power



Outline

- **◆Background**
- **◆Layout Modeling**
- Case Study: RM Cache Design
- Conclusions



Experiment Setup

CPU: 4 simple cores

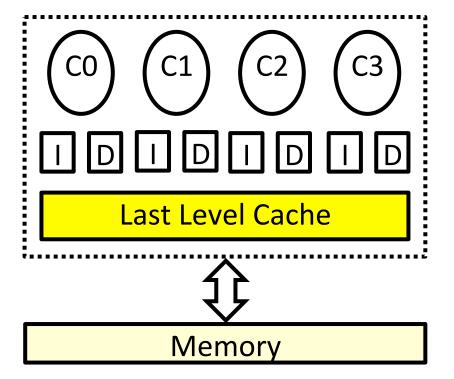
L1: 32KB | & D SRAM

LLC: 64MB RM

Benchmarks: SPEC CPU 2006

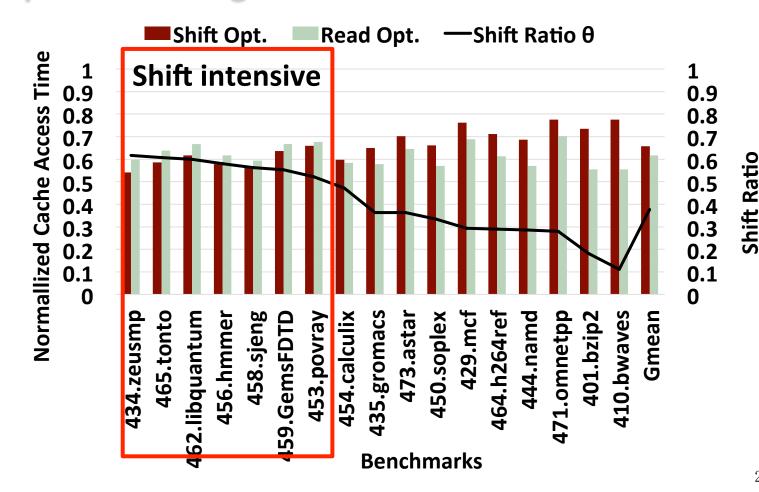
Simulator: gem5

Metric: System execution time



Optimize Read or Shift?

 Application with high shift intensity prefer shift optimized design.



Conclusions

- Racetrack Memory is attractive for ultra high storage density and fast access speed.
- ◆ The design space of Racetrack Memory is really large.
- Our model can facilitate cross-layer co-design.

About the Tool

- Codes will be released
 - http://ceca.pku.edu.cn/chaozhang
 - Suggestions and comments are welcome.
- Future work:
 - Access transistor folding
 - Exploration on racetrack width
 - 3D vertical cells support
 - Reliability simulation
 - •



Thank you! Q & A